

NPN SILICON EPITAXIAL TRANSISTOR (DARLINGTON CONNECTION) FOR LOW-FREQUENCY POWER AMPLIFIERS AND LOW-SPEED SWITCHING

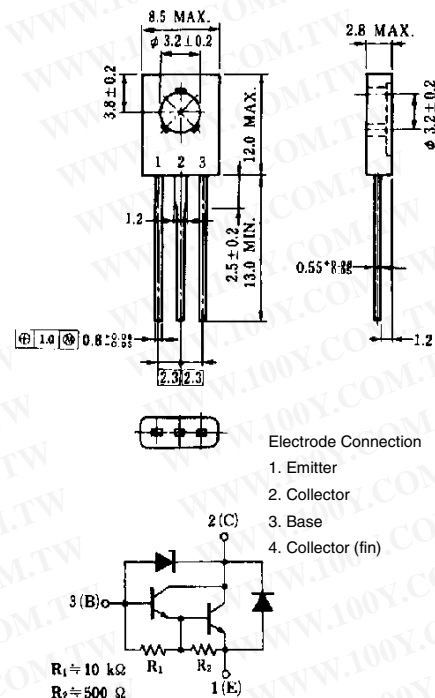
FEATURES

- ## QUALITY GRADES

- Please refer to “Quality Grades on NEC Semiconductor Devices” (Document No. C11531E) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

Parameter	Symbol	Ratings	Unit
Collector to base voltage	V_{CBO}	31 ± 4	V
Collector to emitter voltage	V_{CEO}	31 ± 4	V
Emitter to base voltage	V_{EBO}	8.0	V
Collector current (DC)	$I_{C(DC)}$	± 2.0	A
Collector current (pulse)	$I_{C(pulse)}^*$	± 3.0	A
Base current (DC)	$I_{B(DC)}$	0.2	A
Total power dissipation	$P_T (T_a = 25^\circ C)$	1.3	W
Total power dissipation	$P_T (T_c = 25^\circ C)$	10	W
Junction temperature	T_j	150	$^\circ C$
Storage temperature	T_{stg}	-55 to $+150$	$^\circ C$

PACKAGE DRAWING (UNIT: mm)



勝特力材料 886-3-5753170
勝特力電子(上海) 86-21-54151736
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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

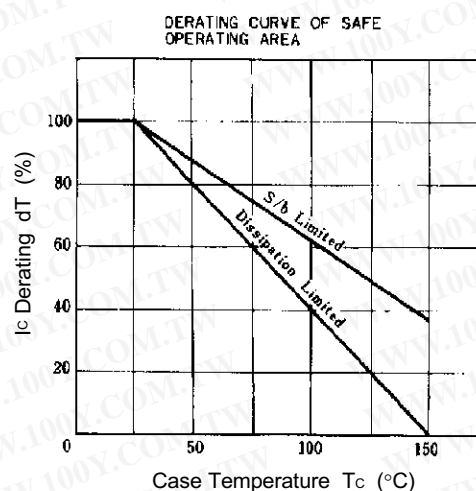
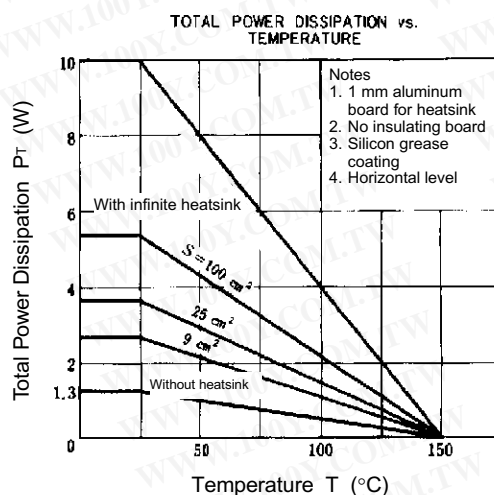
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Collector to base voltage	V _{CB0}	I _C = 1.0 mA, I _E = 0	27	31	35	V
Collector to emitter voltage	V _{CE0}	I _C = 10 mA, R _{BE} = ∞	27	31	35	V
Collector cutoff current	I _{CB0}	V _{CB} = 20 V, I _E = 0			10	μA
DC current gain	h _{FE1} *	V _{CE} = 2.0 V, I _C = 0.5 A	1,000			
DC current gain	h _{FE2} *	V _{CE} = 2.0 V, I _C = 1.0 A	2,000		30,000	
Collector saturation voltage	V _{CE(sat)} *	I _C = 1.0 A, I _B = 1.0 mA		0.9	1.2	V
Base saturation voltage	V _{BE(sat)} *	I _C = 1.0 A, I _B = 1.0 mA		1.6	2.0	V
Turn-on time	t _{on}	I _C = 1.0 A, I _{B1} = -I _{B2} = 5.0 mA R _L = 20 Ω, V _{CC} ≅ 20 V		0.5		μs
Storage time	t _{stg}			3.0		μs
Fall time	t _f			1.0		μs

* Pulse test PW ≤ 350 μs, duty cycle ≤ 2%

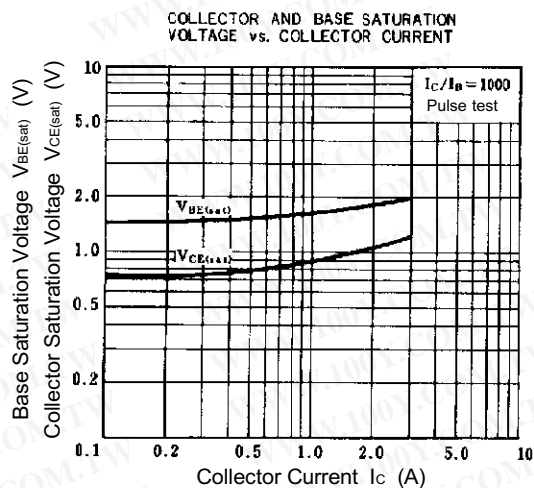
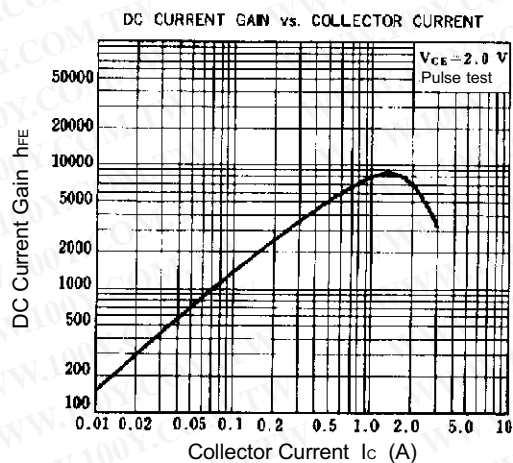
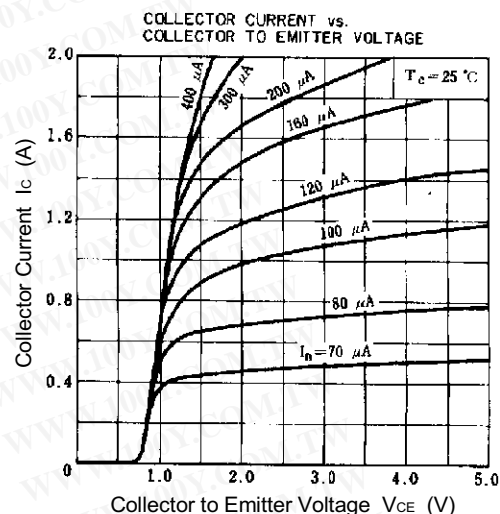
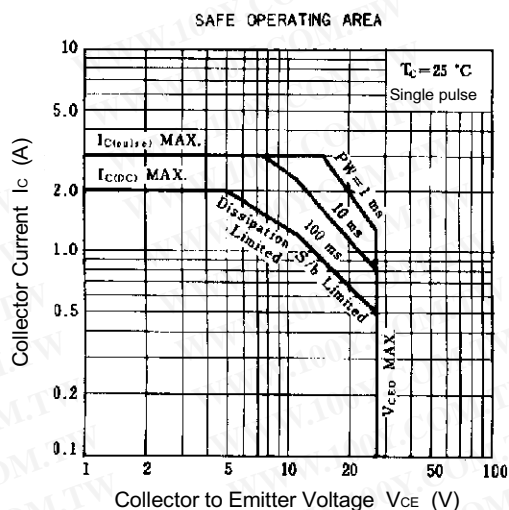
h_{FE2} CLASSIFICATION

Marking	M	L	K
h _{FE2}	2,000 to 5,000	4,000 to 10,000	8,000 to 30,000

TYPICAL CHARACTERISTICS (Ta = 25°C)



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